

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re Application of:

Kiyofumi SAKAGUCHI, et al.

Appln. No.: 10/085,046

Filed: March 1, 2002

For: PROCESS FOR PRODUCTION OF
SEMICONDUCTOR SUBSTRATE

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: Examiner: George R. Fourson, III
)
: Group Art Unit: 2823
)
: Confirmation No.: 7805
)
:
)
: November 7, 2006

Mail Stop Amendment

Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-1450

FIFTH INFORMATION DISCLOSURE STATEMENT

Sir:

In compliance with the duty of disclosure under 37 C.F.R. § 1.56 and in accordance with the practice under 37 C.F.R. §§ 1.97 and 1.98, the Examiner's attention is directed to the documents listed on the enclosed Form PTO-1449. Copies of the listed documents, other than U.S. patent documents, are enclosed.

REMARKS

An English-language Abstract for JP-A 60-196955 was obtained from a commercial database and is also enclosed.

FORMAL MATTERS

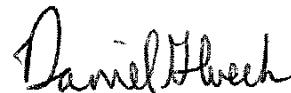
No fee is believed due; however, any fee required in connection with this paper should be charged to Deposit Account No. 06-1205.

CONCLUSION

It is respectfully requested that the above information be considered by the Examiner and that a copy of the enclosed Form PTO-1449 be returned indicating that such information has been considered.

Applicants' undersigned attorney may be reached in our Washington, D.C. office by telephone at (202) 530-1010. All correspondence should continue to be directed to our address given below.

Respectfully submitted,



Attorney for Applicants
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Registration No. 37,838

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30 Rockefeller Plaza
New York, New York 10112-3800
Facsimile: (212) 218-2200

U.S. DEPARTMENT OF COMMERCE
PATENT AND TRADEMARK OFFICELIST OF REFERENCES CITED BY APPLICANT(S)
(Use several sheets if necessary)

Dated Submitted to USPTO: November 7, 2006

APPLICANT
Kiyofumi SAKAGUCHI, et al.FILING DATE
March 1, 2002 GROUP **2823**

U.S. PATENT DOCUMENTS

*EXAMINER INITIAL	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
	5,175,610	12/29/1992	Kobayashi	257	676	
	4,670,763	06/02/1987	Ovshinsky, et al.	357	4	
	4,555,586	11/26/1985	Guha, et al.	136	259	
	4,426,657	01/17/1984	Abiru, et al.	357	29	
	4,064,521	12/20/1977	Carlson	357	2	
	DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION YES/NO/ OR ABSTRACT
	60-196955	10/05/1985	Japan			Abstract
	0 469 630 A2	02/05/1992	Europe			

OTHER DOCUMENT(S) (Including Author, Title, Date, Pertinent Pages, Etc.)

	T. Yasumatsu, et al., "Ultrathin Si Films Grown Epitaxially on Porous Silicon", Applied Surface Science, Vols. 48 & 49, pp. 414-418 (1991)
	Handbook of Thin Film Technology, 5-17 to 5-25 (Eds., L. I. Maissel and R. Glang 1970)
	Robert F. Pierret, Semiconductor Device Fundamentals, pp. 347-368

EXAMINER

DATE CONSIDERED

*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

FORM PTO 1449 (modified) U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE			ATTY DOCKET NO. 03500.010530.5	APPLICATION NO. 10/085,046			
LIST OF REFERENCES CITED BY APPLICANT(S) (Use several sheets if necessary)			APPLICANT Kiyofumi SAKAGUCHI, et al.				
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U.S. PATENT DOCUMENTS							
*EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
FOREIGN PATENT DOCUMENTS							
		DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION YES/NO/ OR ABSTRACT
OTHER DOCUMENT(S) (Including Author, Title, Date, Pertinent Pages, Etc.)							
		S.M. Sze, Physics of Semiconductor Devices, pp. 63-128, 847-849, 2nd Edition (1981)					
		W. Kern & V. Ban, Thin Film Processes, Chemical Vapor Deposition of Inorganic Thin Films, pp. 257-331 (1978)					
		W. Luft & Y. Tsuo, Hydrogenated Amorphous Silicon Alloy Deposition Processes, pp. 125-144 (1993)					
		R. Pierret, Modular Series on Solid State Devices, Vol. 4, pp. 59-80 (1983)					
EXAMINER			DATE CONSIDERED				

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Sheet 2 of 2